

**Search Notes**

Application/Control No.

10/668,225

Examiner

Christopher B. Shin

Applicant(s)/Patent under  
Reexamination

ODAKURA ET AL.

Art Unit

2182

**SEARCHED**

Class	Subclass	Date	Examiner
710	52-57	6/20/2005	CBS
360	46,53,75	6/20/2005	CBS
711	202,218	6/20/2005	CBS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PALM SEARCHED FOR DOUBLE PATNETING	6/17/2005	CBS
PLUS	6/21/2005	CBS
EAST (USPAT, USPGPUB, USPAT, EPO, JPO, DERWENT, IBMTDB, USOCR	6/20/2005	CBS